- Compares Two 8-Bit Words
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Plastic Shrink Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

description

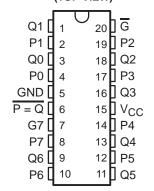
These identity comparators perform comparisons on two 8-bit binary or BCD words. Also included is a $\overline{P} = \overline{Q}$ totem-pole output.

The 54AC11521 is characterized for operation over the full military temperature range of -55° C to 125°C. The 74AC11521 is characterized for operation from -40° C to 85° C.

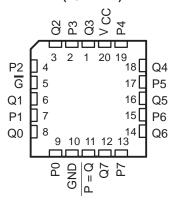
FUNCTION TABLE

INF	PUTS	OUTPUT
DATA P, Q	ENABLE G	P = Q
P = Q	L	L
P > Q	L	Н
P < Q	L	Н
Х	Н	Н

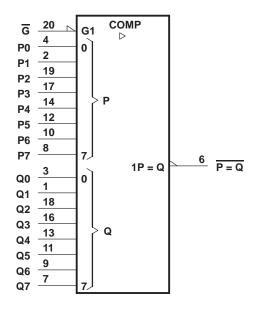
54AC11521 . . . J PACKAGE 74AC11521 . . . DB, DW OR N PACKAGE (TOP VIEW)



54AC11521 . . . FK PACKAGE (TOP VIEW)



logic symbol†



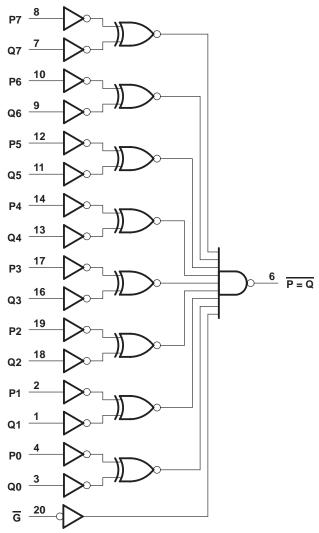
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pins numbers shown are for the DW, J, and N packages.

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logic diagram (positive logic)



Pin numbers shown are for the DW, J, and N packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 6 V
Input voltage range, V _I (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V _O (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	± 20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	± 50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	
Continuous current through V _{CC} or GND	±100 mA
Storage temperature range	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



recommended operating conditions

			54	AC1152	:1	74AC11521		UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		3	5	5.5	3	5	5.5	V
		V _{CC} = 3 V	2.1			2.1			
VIH	IH High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V
		V _{CC} = 5.5 V	3.85			3.85			
V _{IL} Low-level input voltage		V _{CC} = 3 V			0.9			0.9	
	V _{CC} = 4.5 V			1.35			1.35	V	
		V _{CC} = 5.5 V			1.65			1.65	
VI	Input voltage		0		VCC	0		VCC	V
VO	Output voltage		0		VCC	0		VCC	V
		VCC = 3 V			- 4			- 4	
IOH	High-level output current	V _{CC} = 4.5 V			- 24			- 24	mA
		V _{CC} = 5.5 V			-24			-24	
		V _{CC} = 3 V			12			12	
I _{OL} L	Low-level output current	V _{CC} = 4.5 V			24			24	mA
		V _{CC} = 5.5 V			24			24	
Δt/Δν	Input transition rise or fall rate		0		10	0		10	ns/V
TA	Operating free-air temperature		-55		125	- 40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		T,	4 = 25°C	;	54AC1	1521	74AC11521		LINIT
FARAMETER		TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX
		3 V	2.9			2.9		2.9		
	ΙΟΗ = - 50 μΑ	4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
M	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.4		2.48		.,
VOH	I _{OH} = – 24 mA	4.5 V	3.94			3.7		3.8		V
	10H = - 24 IIIA	5.5 V	4.94			4.7		4.8		
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	I _{OH} = - 75 mA [†]	5.5 V						3.85		
	I _{OL} = 50 μA	3 V			0.1		0.1		0.1	
		4.5 V			0.1		0.1		0.1	
		5.5 V			0.1		0.1		0.1	
V	I _{OL} = 12 mA	3 V			0.36		0.5		0.44	.,
V_{OL}	10. 24.50	4.5 V			0.36		0.5		0.44	V
	I _{OL} = 24 mA	5.5 V			0.36		0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65			
	I _{OL} = 75 mA [†]	5.5 V							1.65	
II	$V_I = V_{CC}$ or GND	5.5 V			± 0.1		± 1		± 1	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		160		80	μΑ
Ci	$V_I = V_{CC}$ or GND	5 V		4						pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

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switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	4 = 25°C	;	54AC1	1521	74AC1	1521	UNIT	
PARAMETER	(INPUT) (OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
^t PLH	P or Q		1.5	12.5	16.6	1.5	20.4	1.5	19		
t _{PHL}	Forq	P = Q	P=Q	1.5	10.5	14.1	1.5	17.4	1.5	16.1	ns
t _{PLH}	G		1.5	7.1	9.8	1.5	11.4	1.5	10.8		
t _{PHL}		P = Q	1.5	6.4	8.8	1.5	10.8	1.5	10.1	ns	

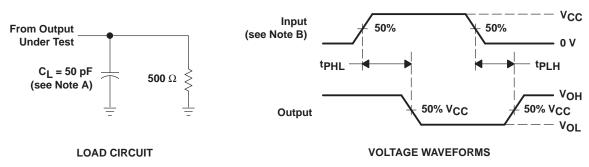
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

I PARAMETER I	FROM		T,	չ = 25°C	;	54AC1	11521	74AC1	1521	UNIT		
	(INPUT)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
t _{PLH}	D or O		1.5	8.3	11.3	1.5	14	1.5	13	no		
^t PHL	P or Q	P = Q	P=Q	P=Q	1.5	7.2	10.1	1.5	12.2	1.5	11.4	ns
t _{PLH}	G	-	1.5	5.1	7.1	1.5	8.4	1.5	7.9			
t _{PHL}	G	P = Q	1.5	4.8	7.1	1.5	8.6	1.5	8.1	ns		

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	$C_L = 50 \text{ pF}, \qquad \qquad f = 1 \text{ MHz}$	42	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \ \Omega$, $t_f = 3 \ ns$, $t_f = 3 \ ns$.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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